

A 0.048-mm² 3-mW Synthesizable Fractional-*N* PLL with a Soft Injection-Locking Technique

Wei Deng, Dongsheng Yang, Aravind Tharayil Narayanan, Kengo Nakata, Teerachot Siriburanon, Kenichi Okada, and Akira Matsuzawa

Tokyo Institute of Technology, Japan

Outline

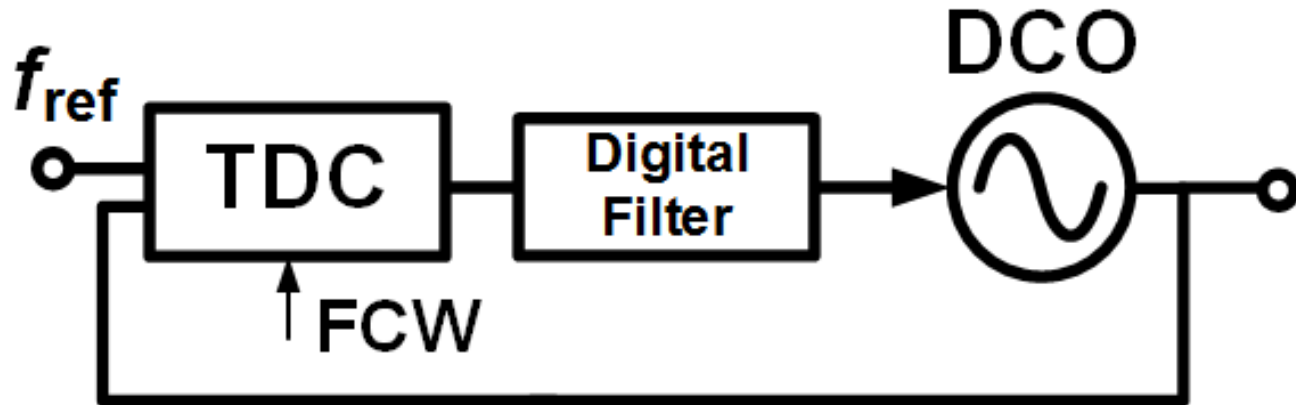
- Introduction
- Concept of **Soft Injection Locking**
- Circuit Implementations
- Measurement Results
- Conclusion

Introduction

- **Why High Performance PLL**
 - **Clock generation/distribution**
- **Key Specifications for SoC Clocking**
 - **Small area**
 - **Low power consumption**
 - **Low jitter**
 - **Insensitive over environment variations**
 - **Scalable with technology advancement**

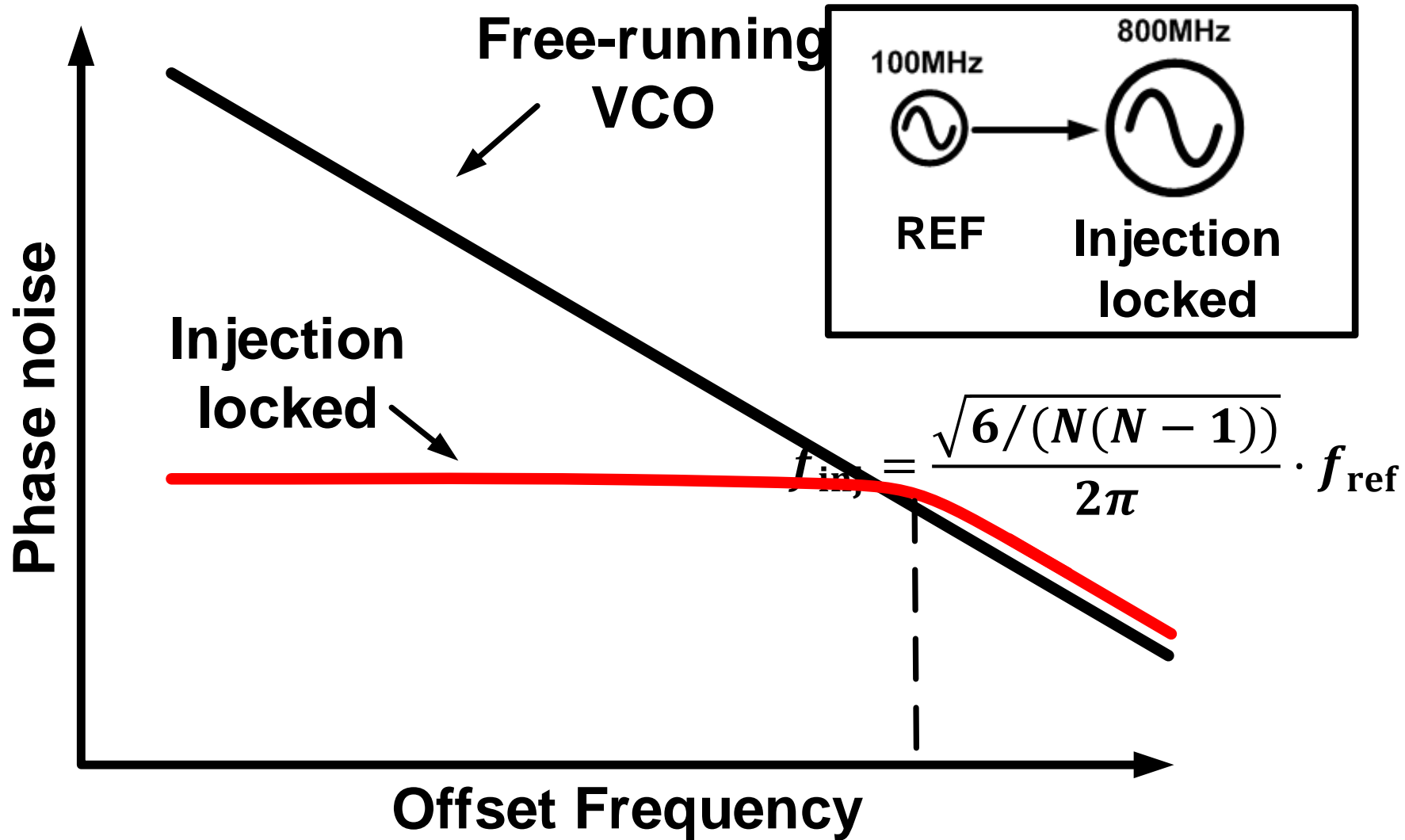
All-digital PLLs

- TDC-based architecture



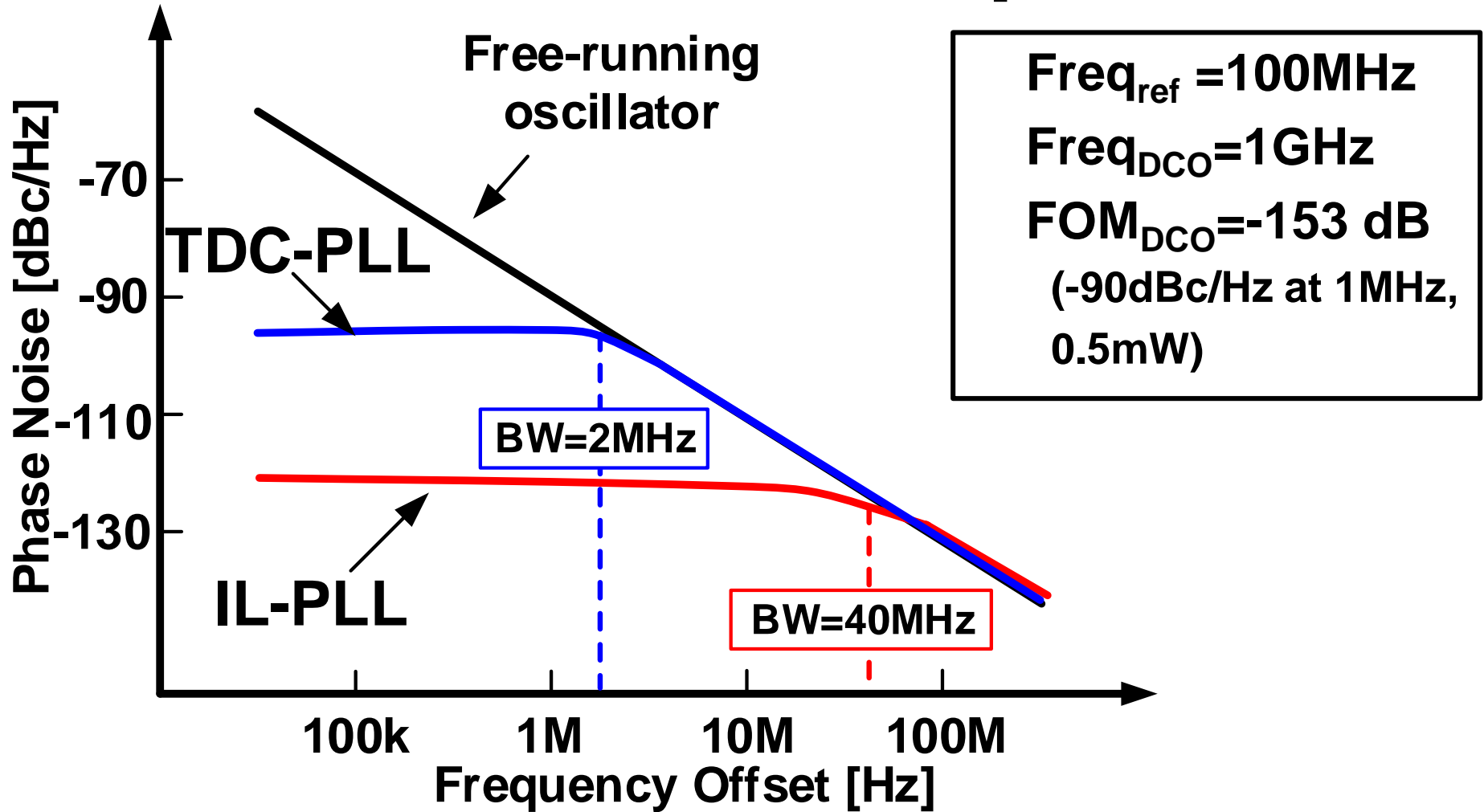
- ☺ – Taking advantages of digital circuits
- ☺ – Compact chip area
- ☹ – Cannot fully utilize digital design flow
 - Layout uncertainty caused by Auto Place & Route degrades TDC and DCO linearity.

Injection Locking Technique



[N.D. Dalt, TCAS II 2014]

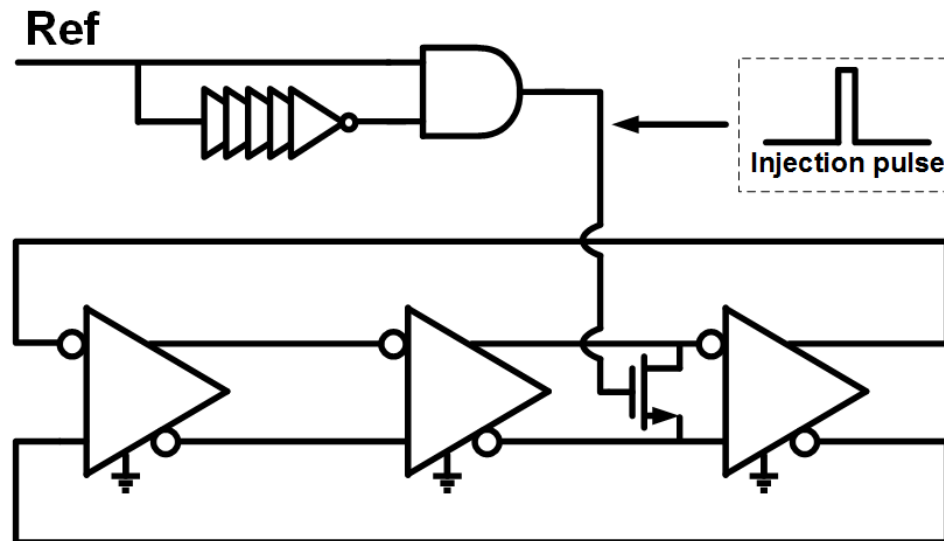
Phase Noise Comparison



- $Jitter_{TDC-PLL} = 6.4\text{ps}$ $Jitter_{IL-PLL} = 1.5\text{ps}$

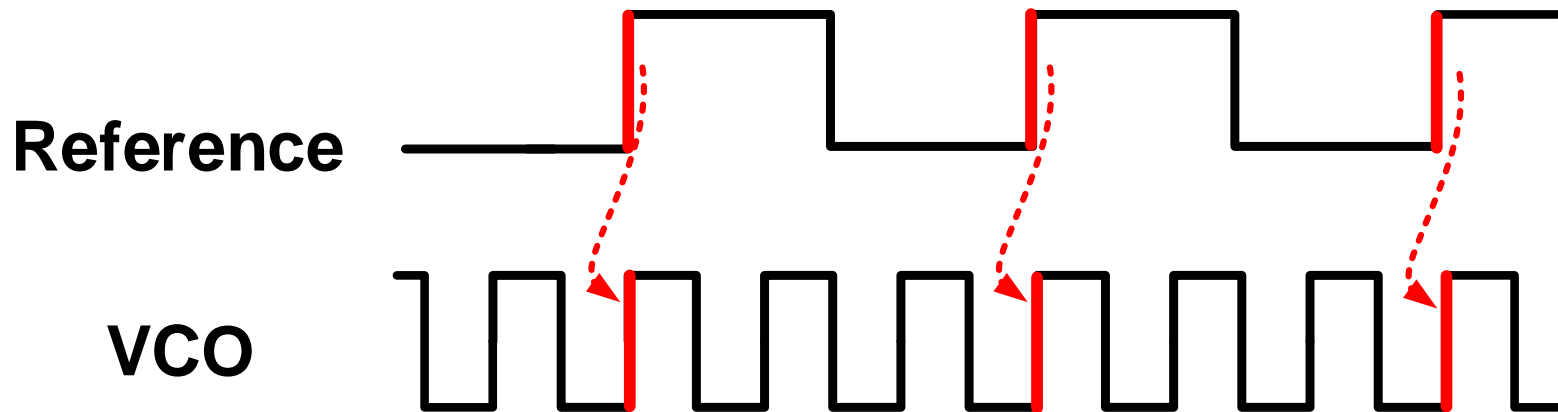
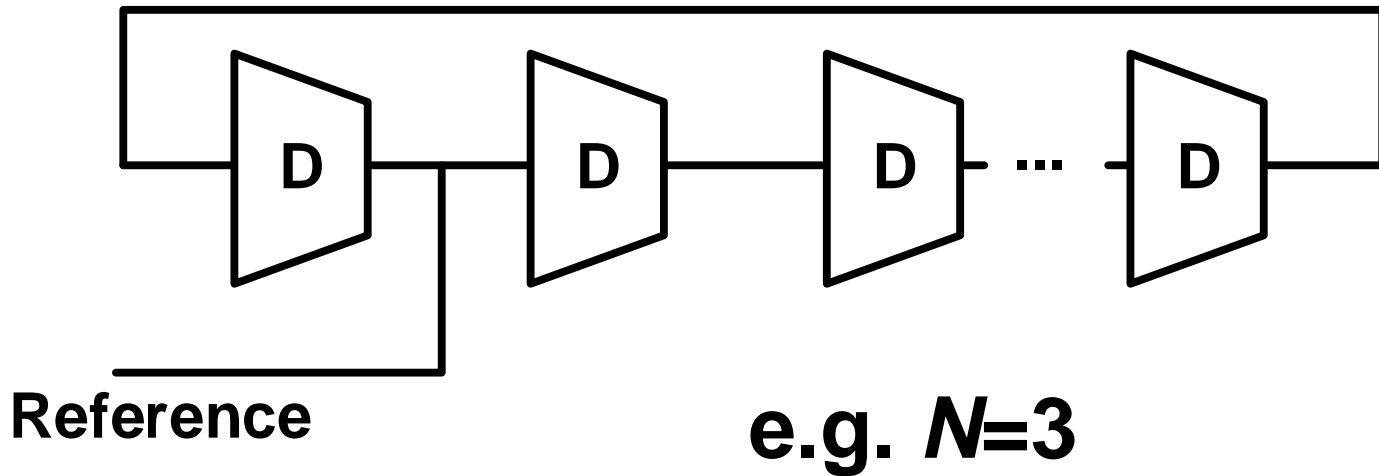
Injection Method

- **Pulse Injection** [B. Helal, *et al.*, JSSC 2009]

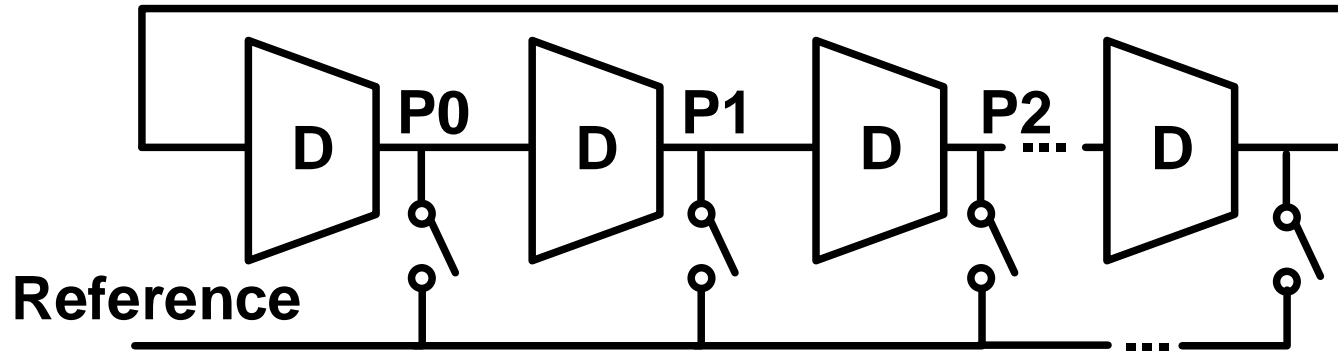


- **Multiplying DLL** [S. Ye, *et al.*, JSSC 2002]
- **Edge Injection** [W. Deng, *et al.*, ISSCC 2014]

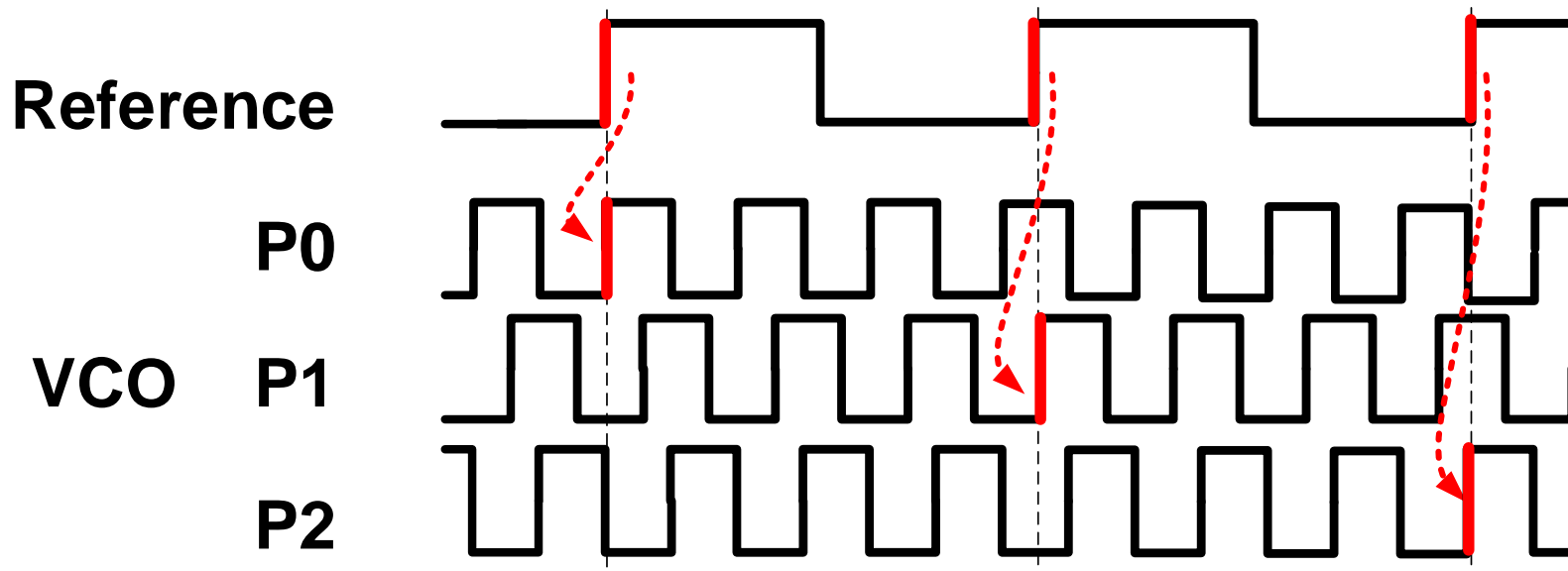
Integer- N Operation



Sub-Integer-N Operation



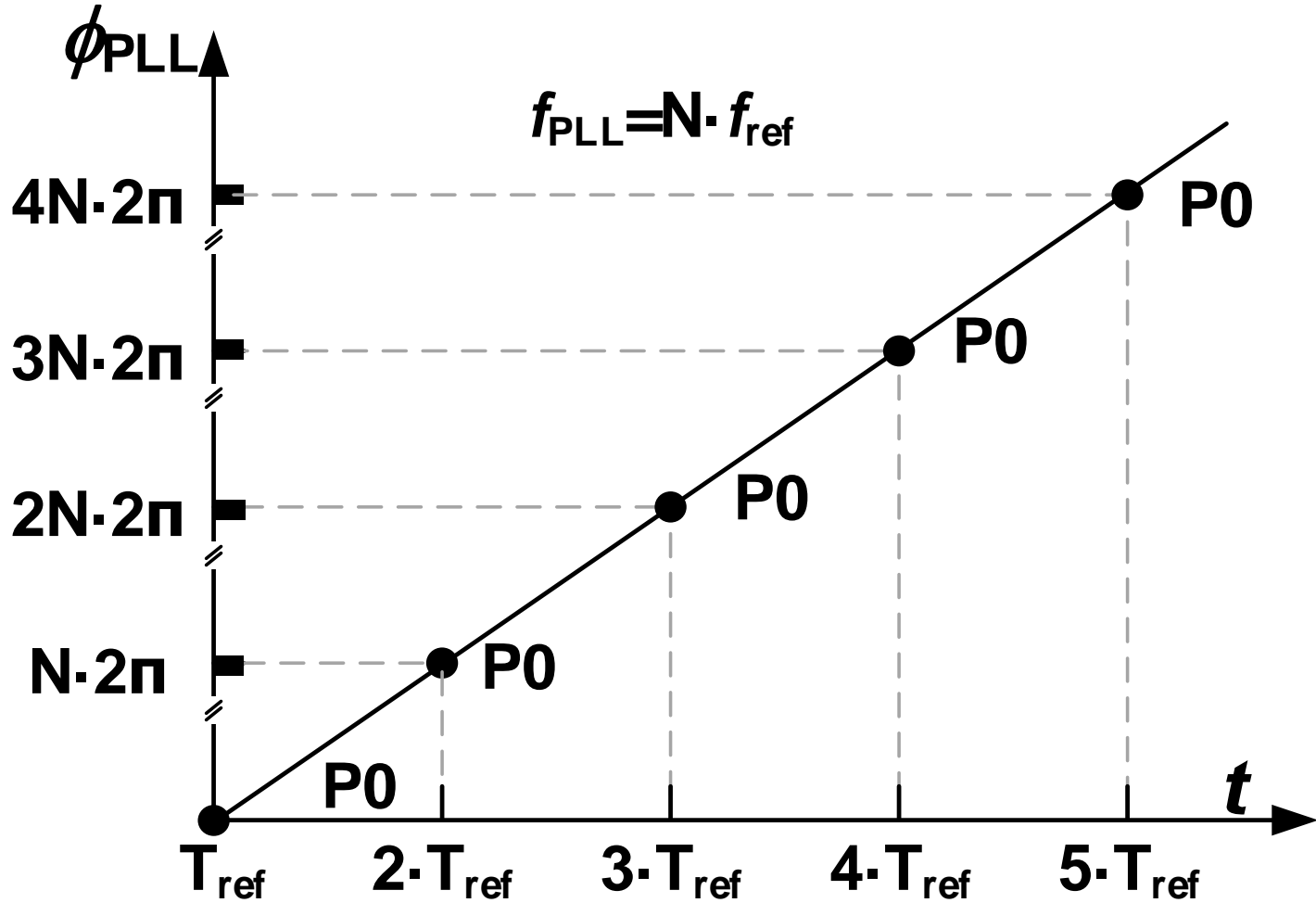
e.g. $N=3+(1/M)$



[P. Park, et al., ISSCC 2012]

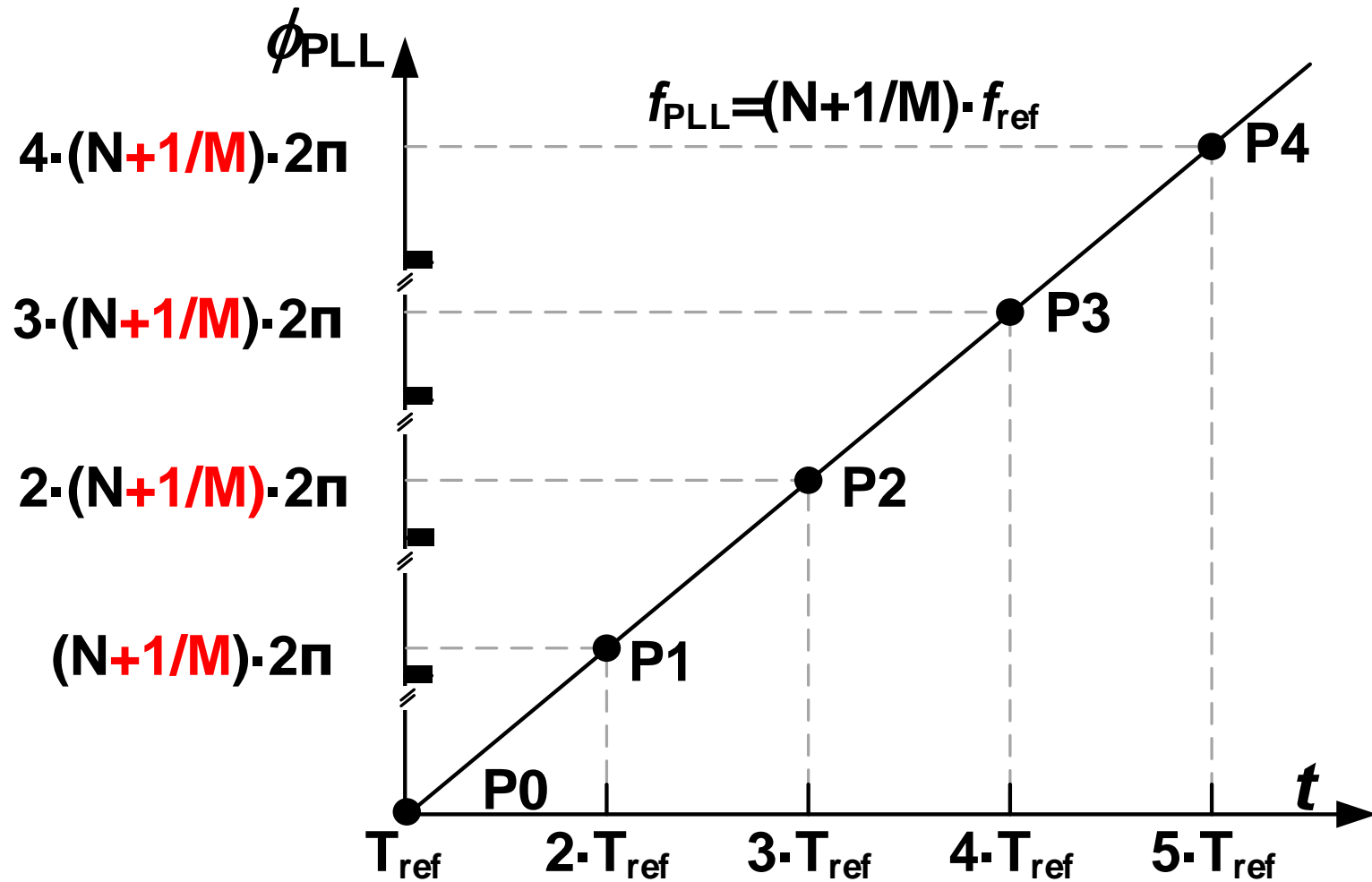


Phase Domain (Integer- N)



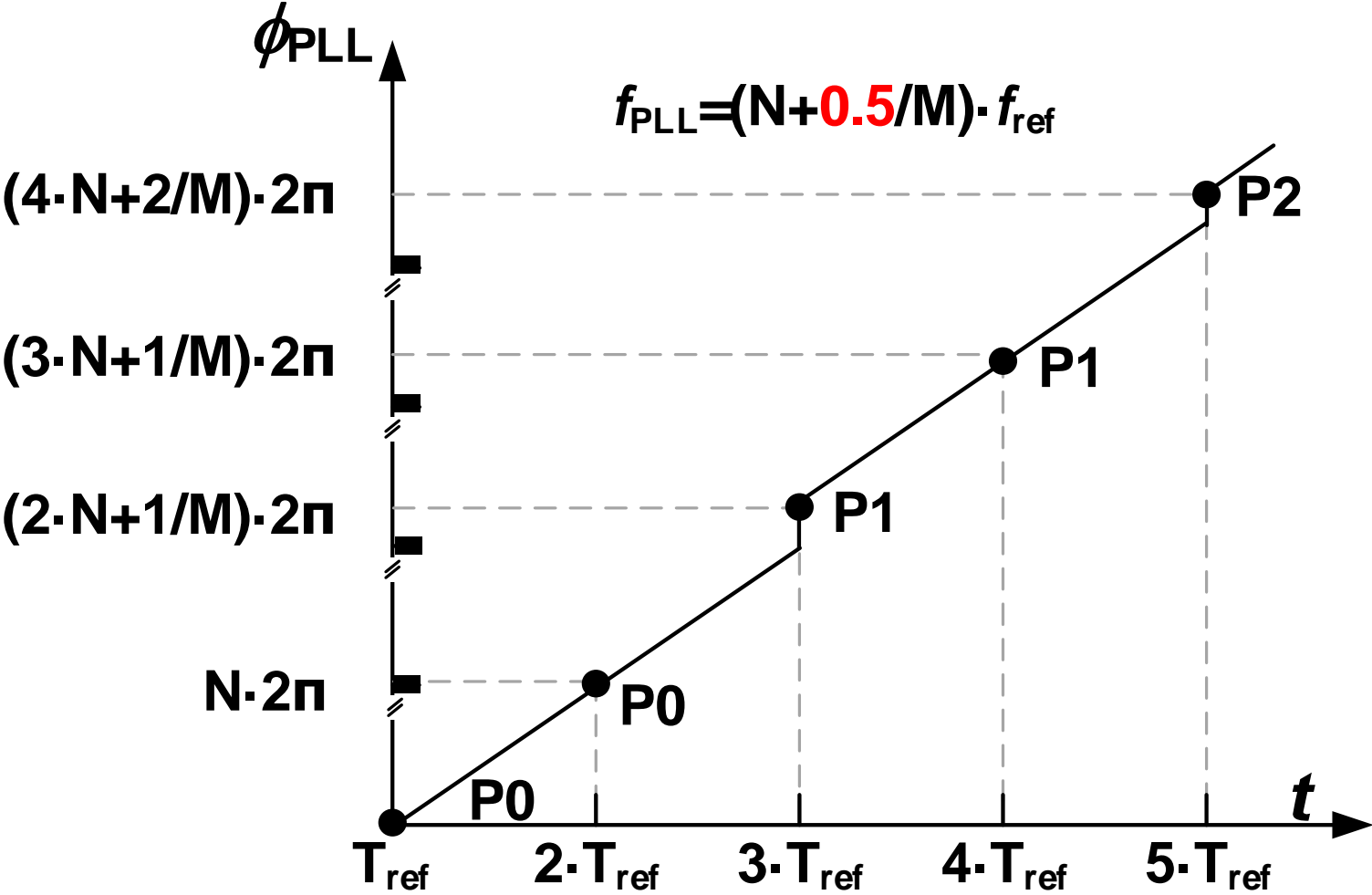
$P0 \rightarrow P0 \rightarrow P0 \rightarrow P0 \rightarrow P0 \rightarrow P0 \rightarrow P0 \rightarrow P0 \dots$

Phase Domain (Sub-Integer- M)



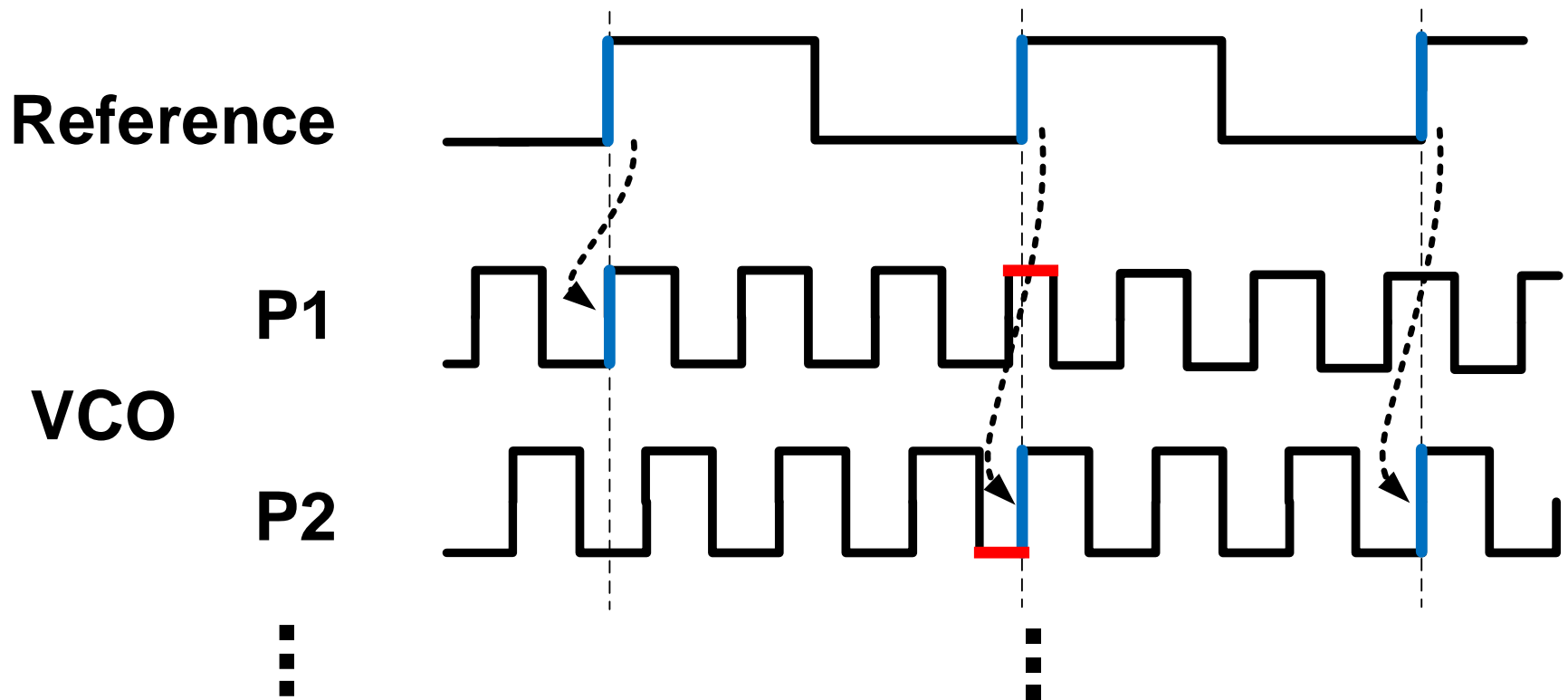
$P_0 \rightarrow P_1 \rightarrow P_2 \rightarrow P_3 \rightarrow \dots \rightarrow P_0 \rightarrow P_1 \dots$

Phase Domain (Fractional-N)



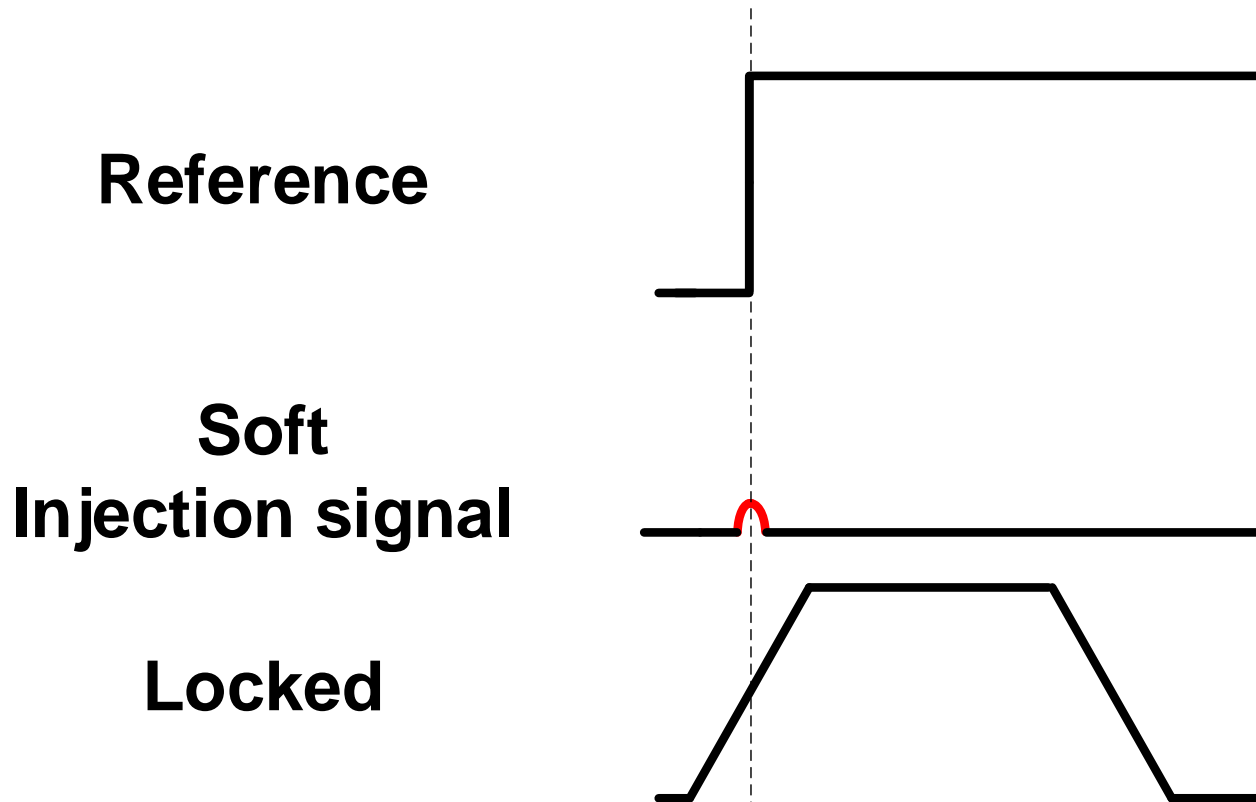
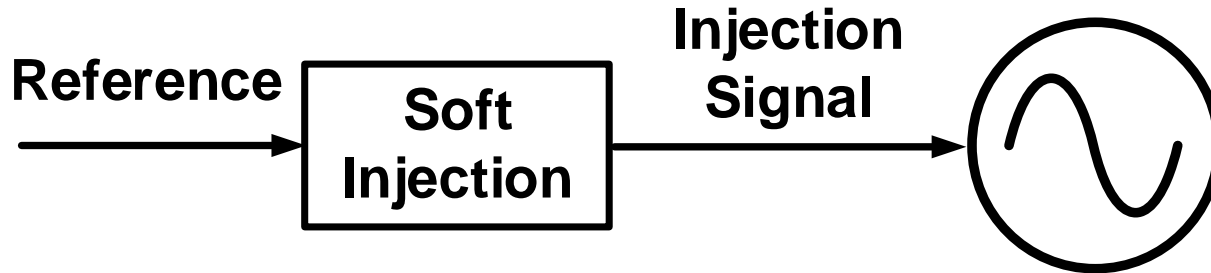
$P_0 \rightarrow P_0 \rightarrow P_1 \rightarrow P_1 \rightarrow P_2 \rightarrow P_2 \rightarrow P_3 \dots$

Time Domain (Fractional-N)



- Spur is caused by “hard” switching

Proposed Soft Injection



“Hard” vs “Soft” Injection

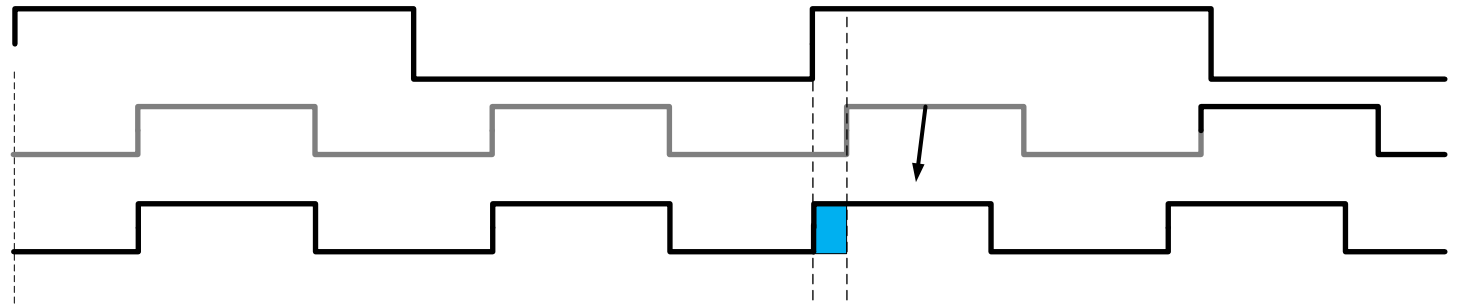
Injection at ϕ_0

Injection at ϕ_{10}

Reference

ϕ_{10} w/o inj

ϕ_{10} w/ inj

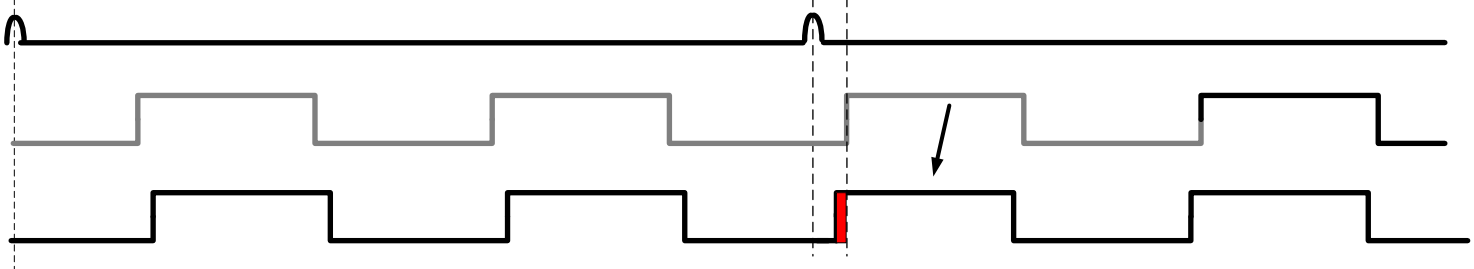


Conventional “hard” injection

Soft injection

ϕ_{10} w/o inj

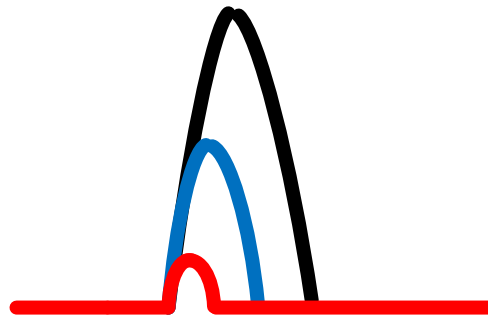
ϕ_{10} w/ inj



Proposed “**soft**” injection

Injection Strength

- **Soft injection signal level determines injection strength**



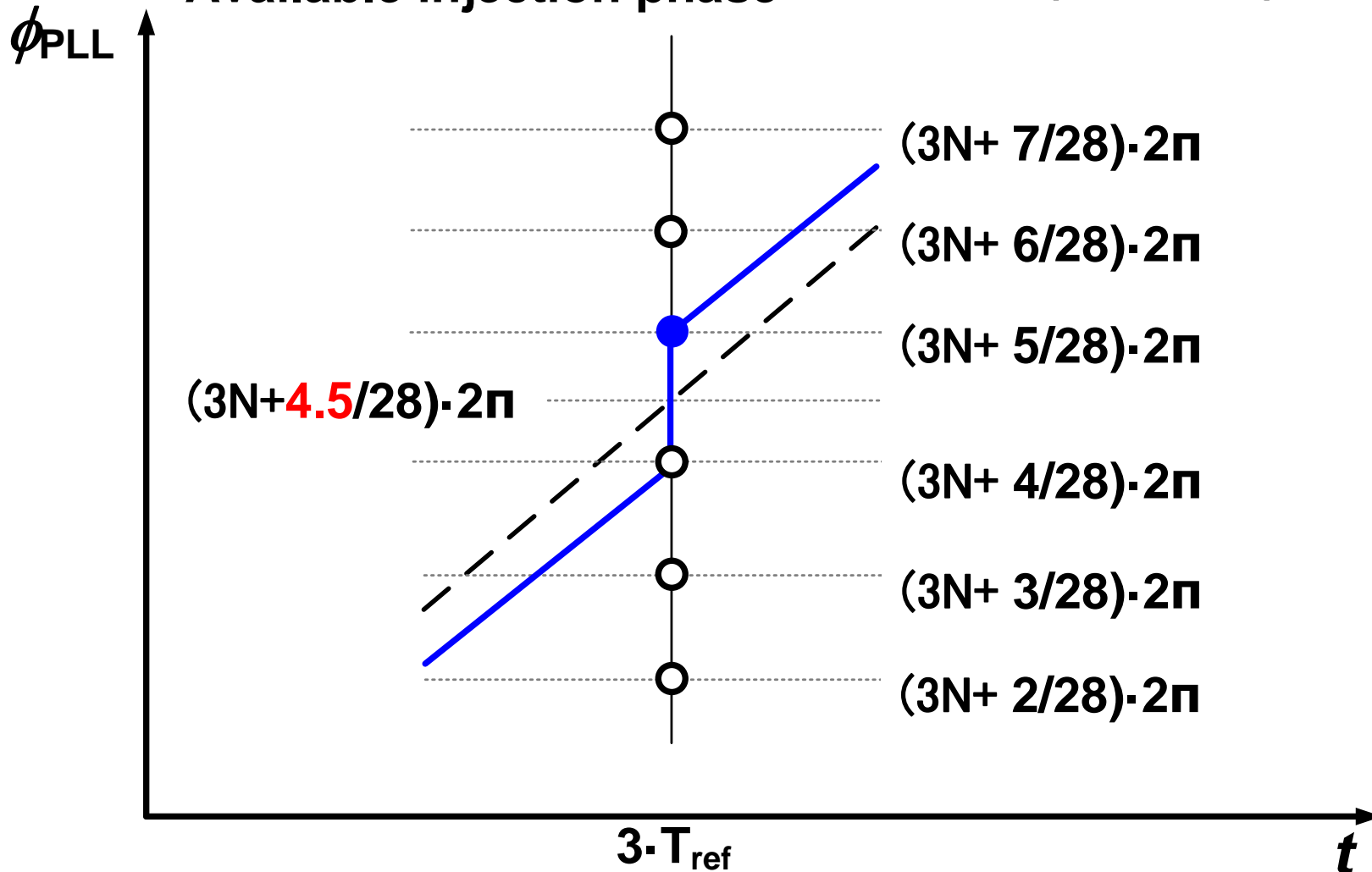
Soft Injection Signal

- **Stronger injection strength leads to larger phase shift**

Fractional-N Operation (Hard)

- Selected injection phase
- Available injection phase

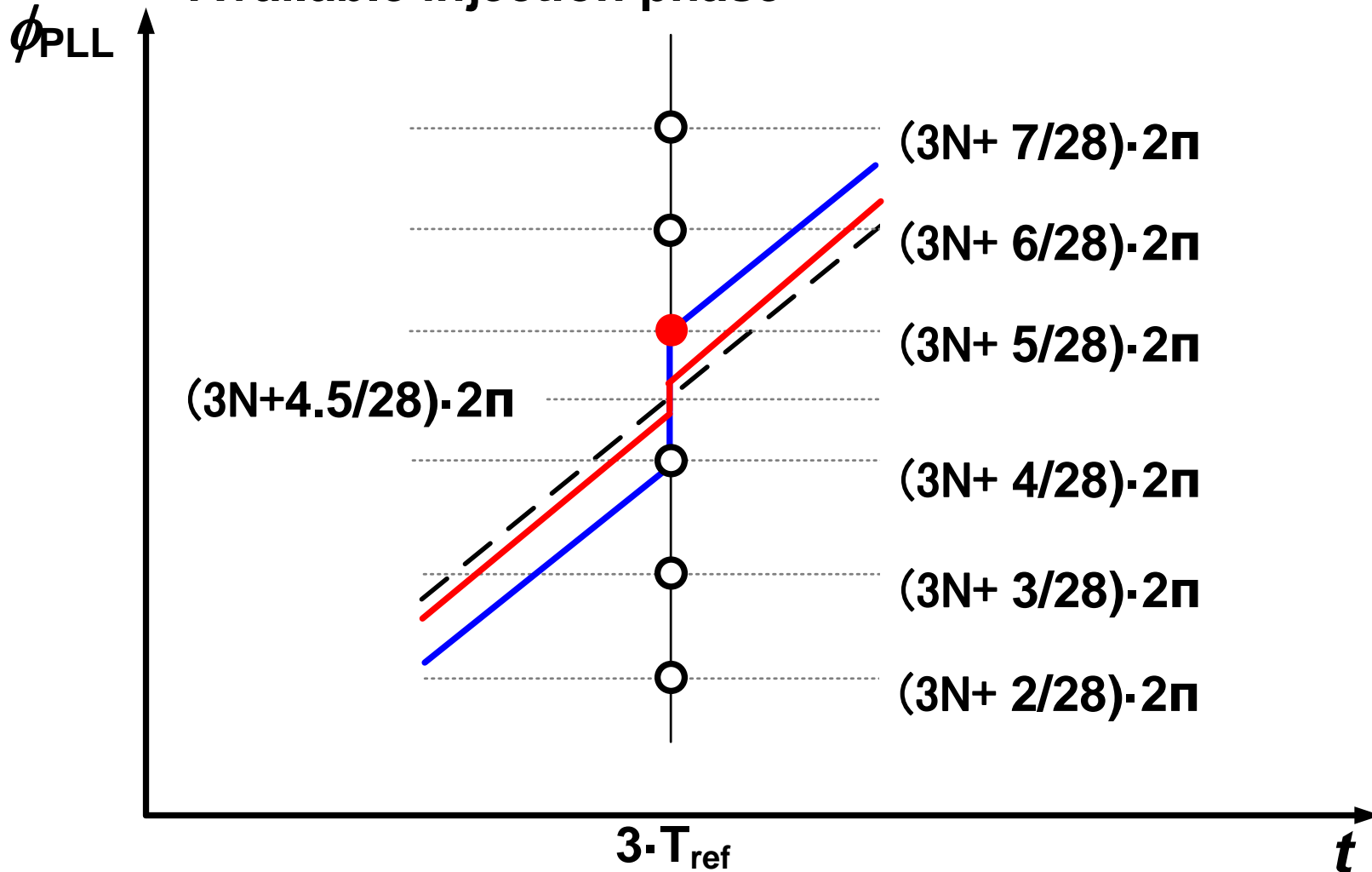
$$f_{\text{PLL}} = (N + 1.5/28) \cdot f_{\text{ref}}$$



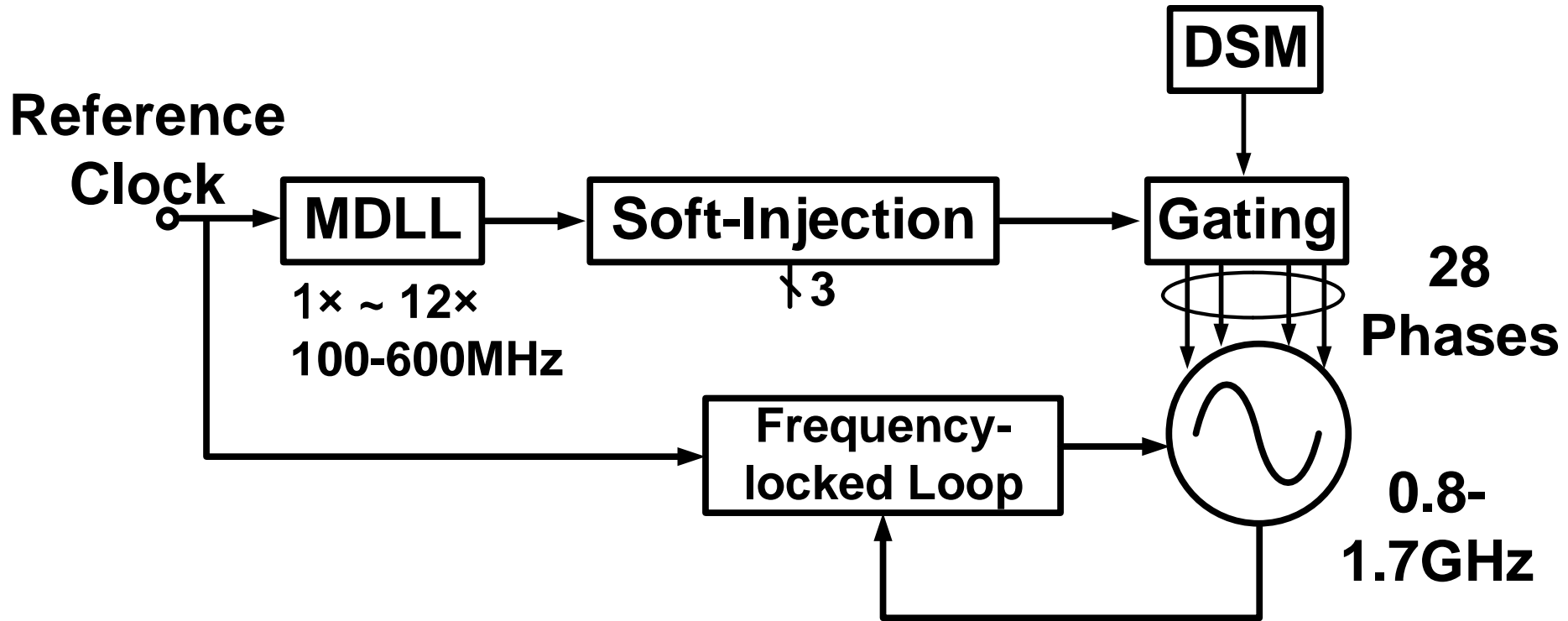
Fractional-N Operation (Soft)

- Selected injection phase
- Available injection phase

$$f_{\text{PLL}} = (N + 1.5/28) \cdot f_{\text{ref}}$$

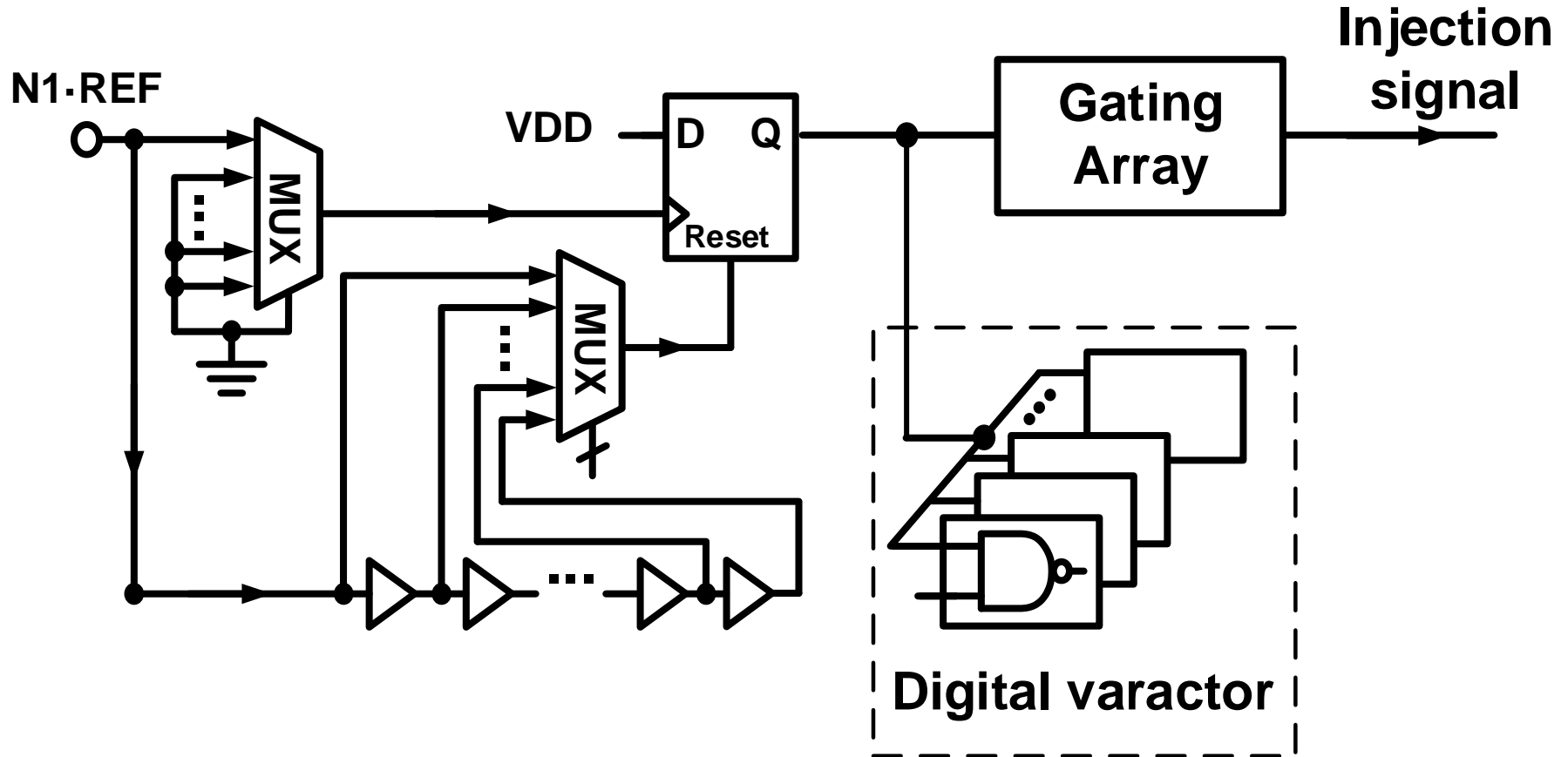


PLL with Soft Injection



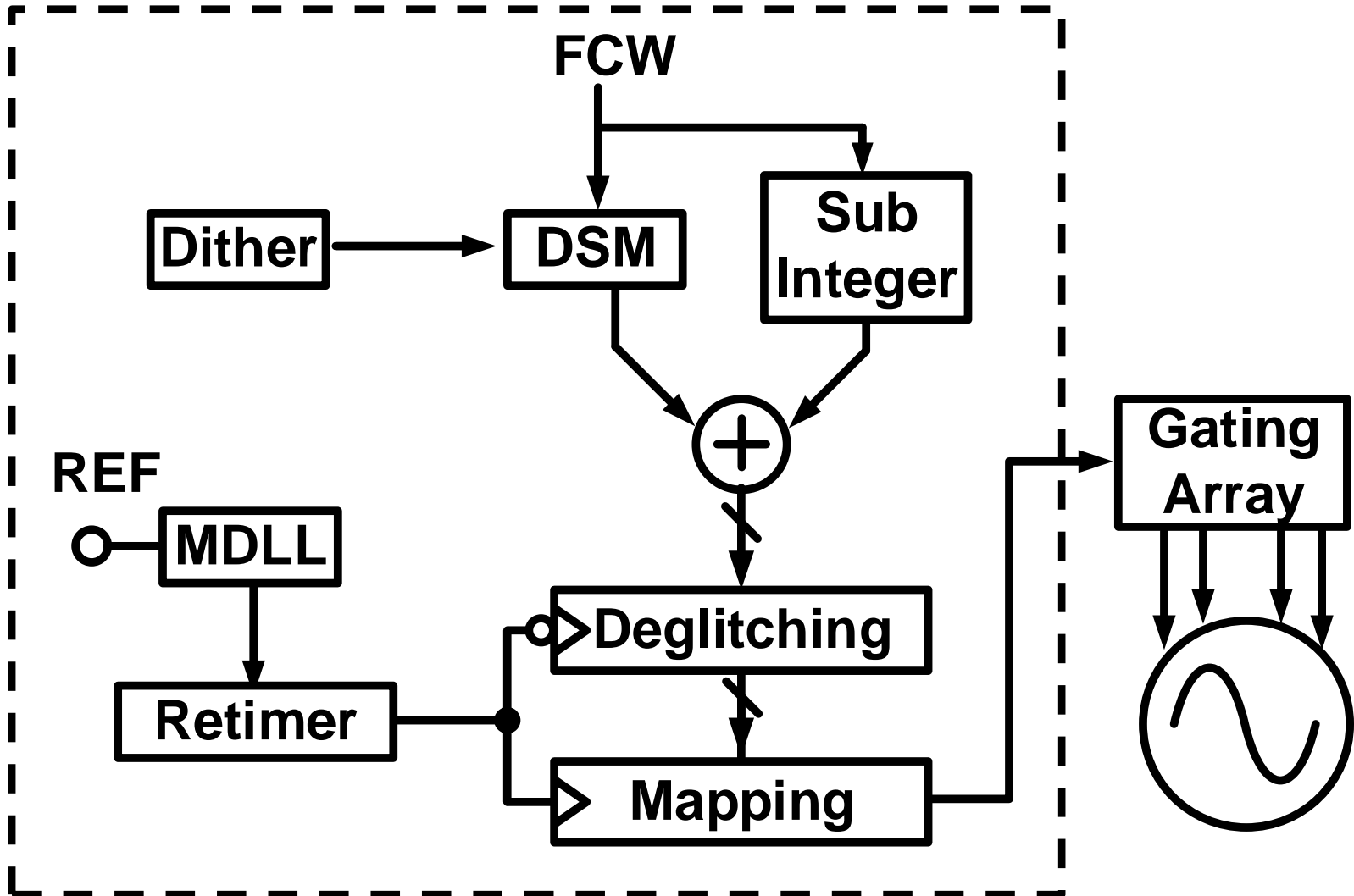
- Cascading topology

Soft Injection Generator

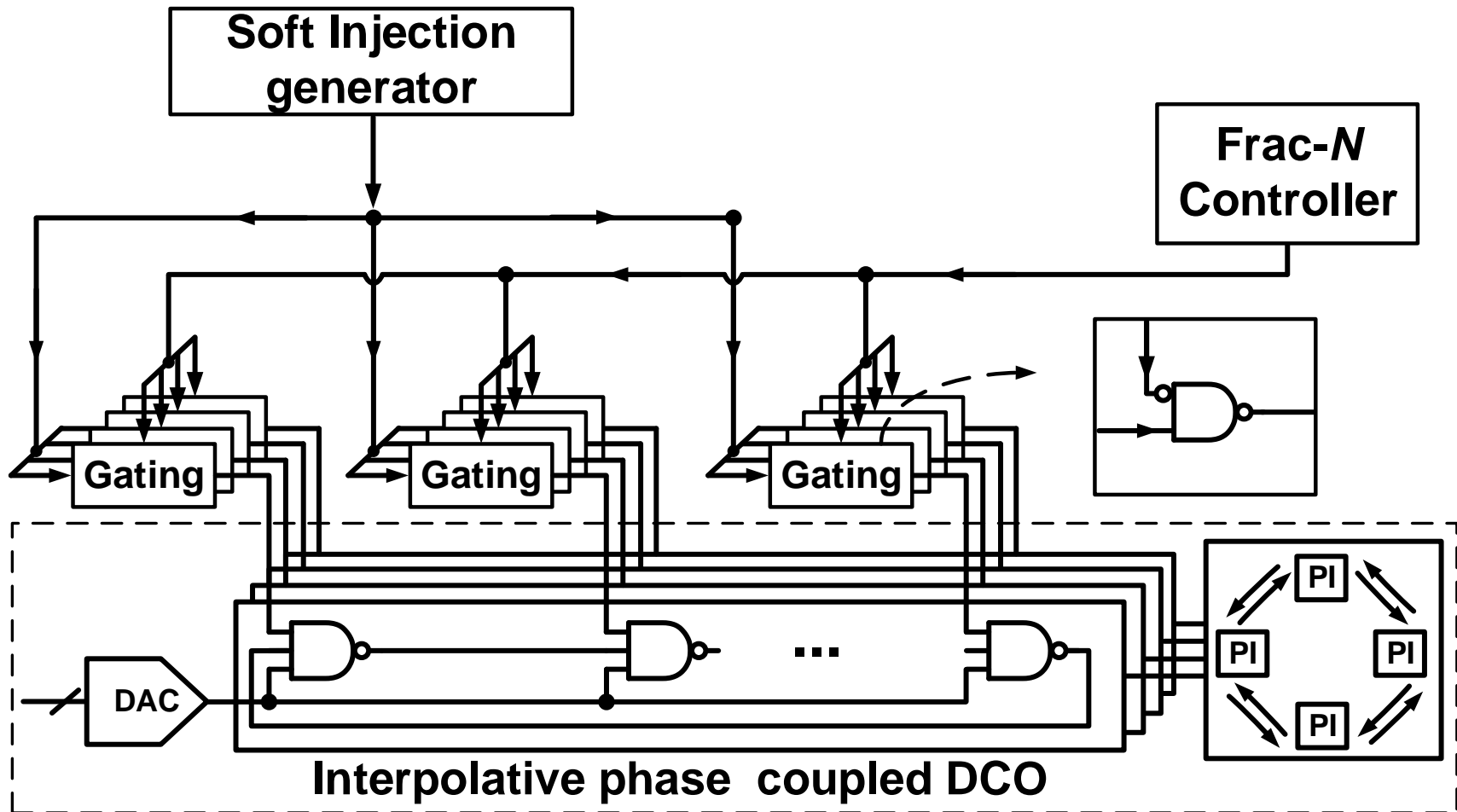


- Effective soft injection signal is generated by soft injection generator and gating array.

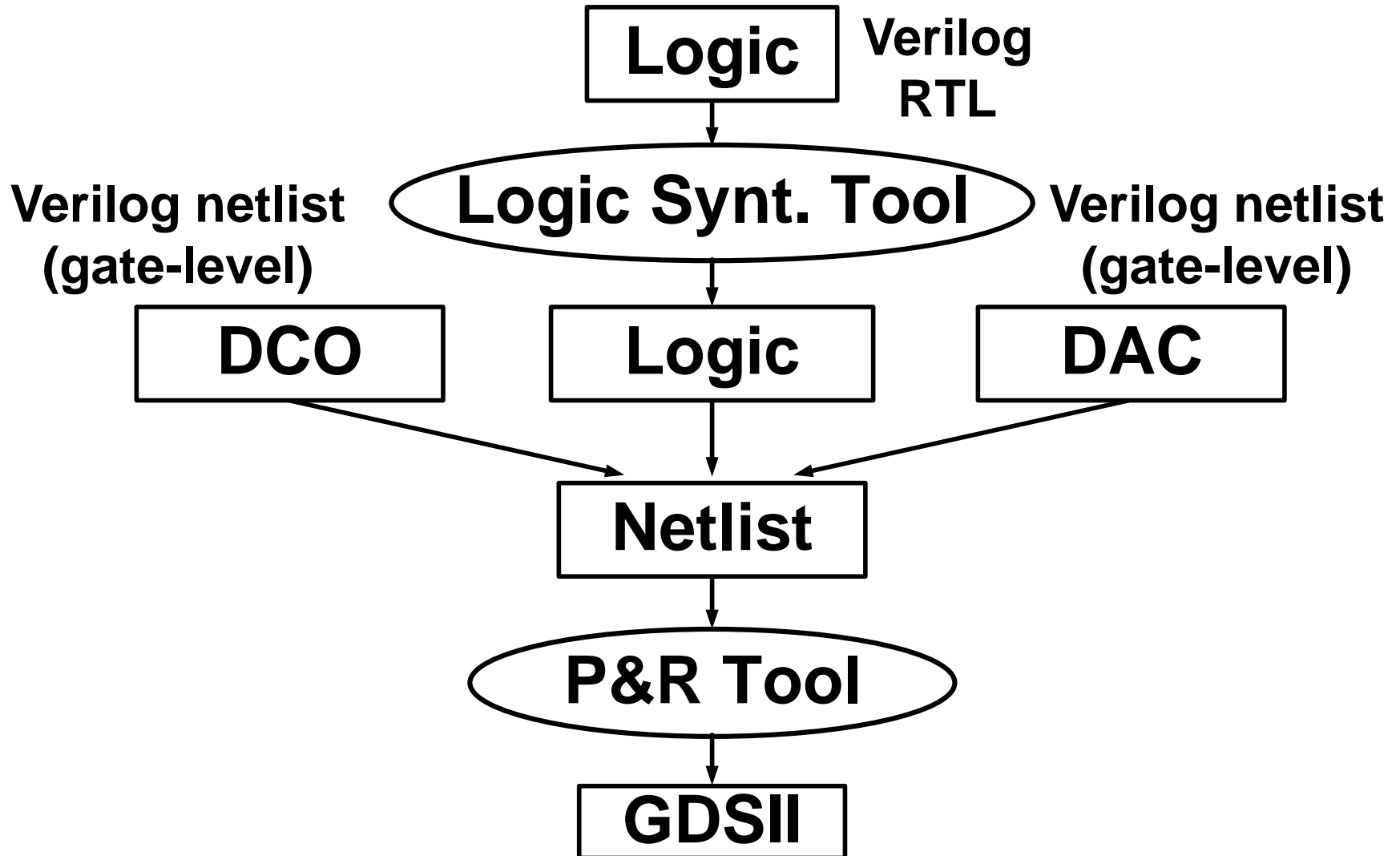
Fractional-N Controller



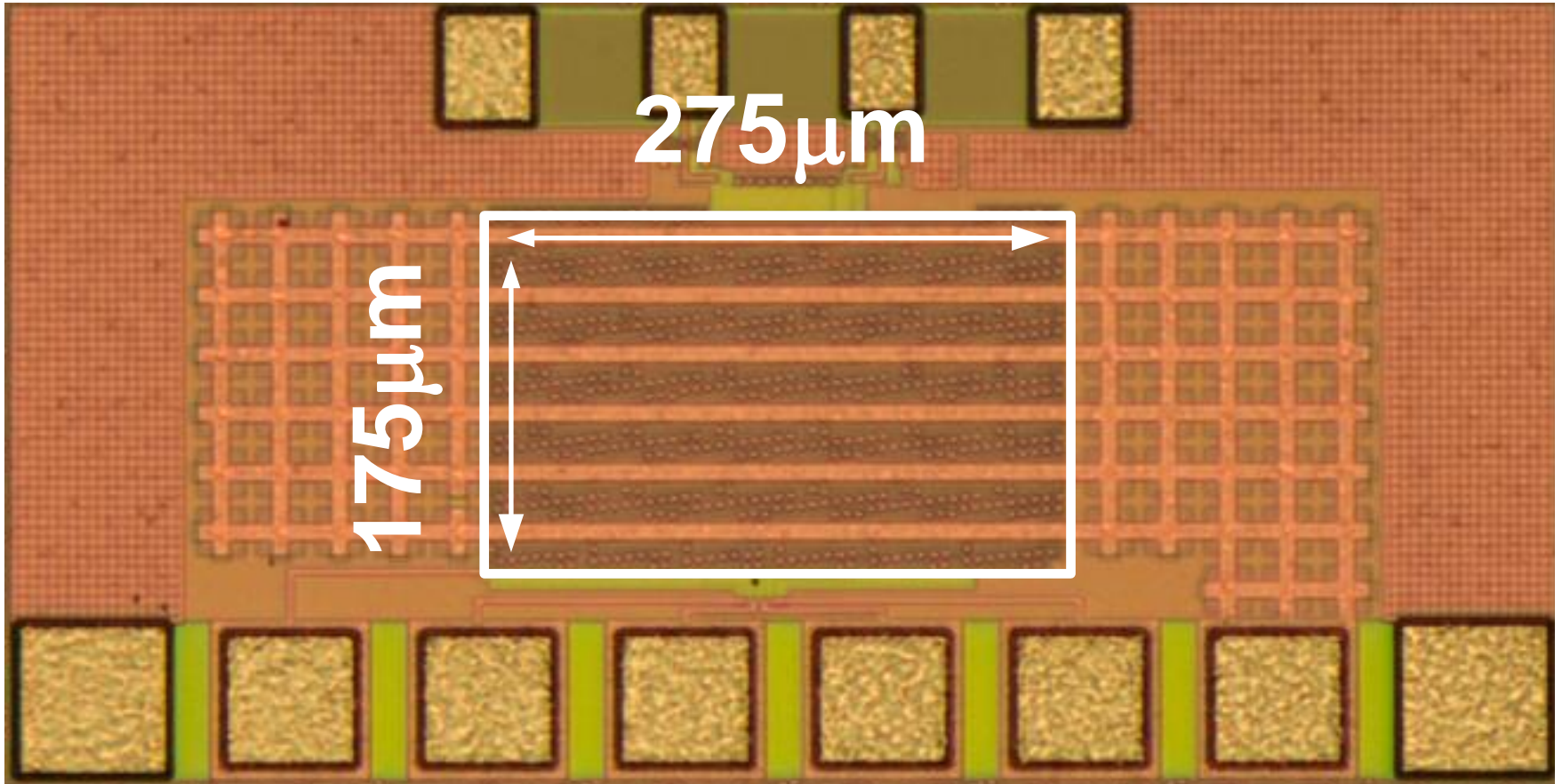
Gating Array



Design Procedure

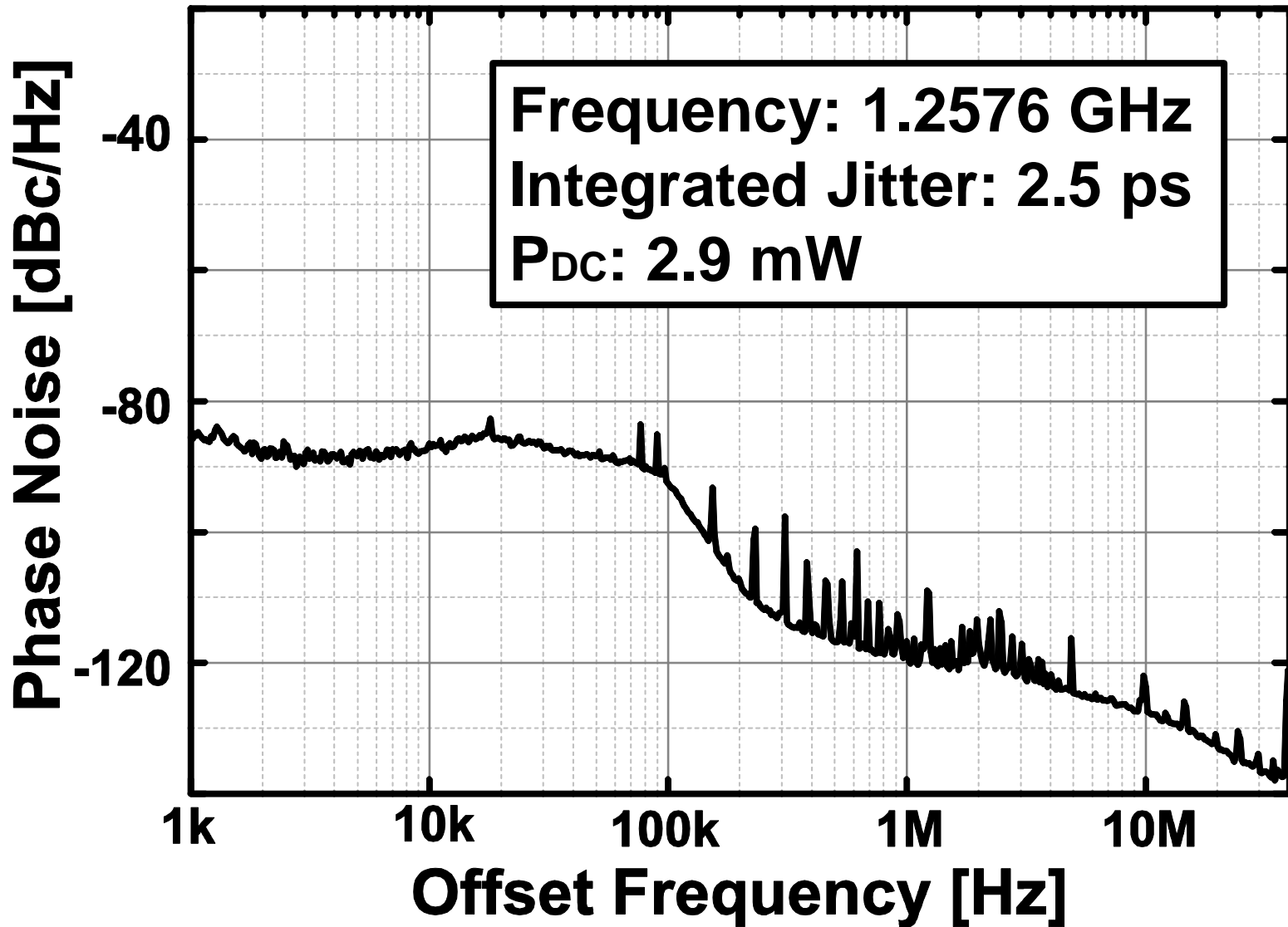


Chip Microphotograph

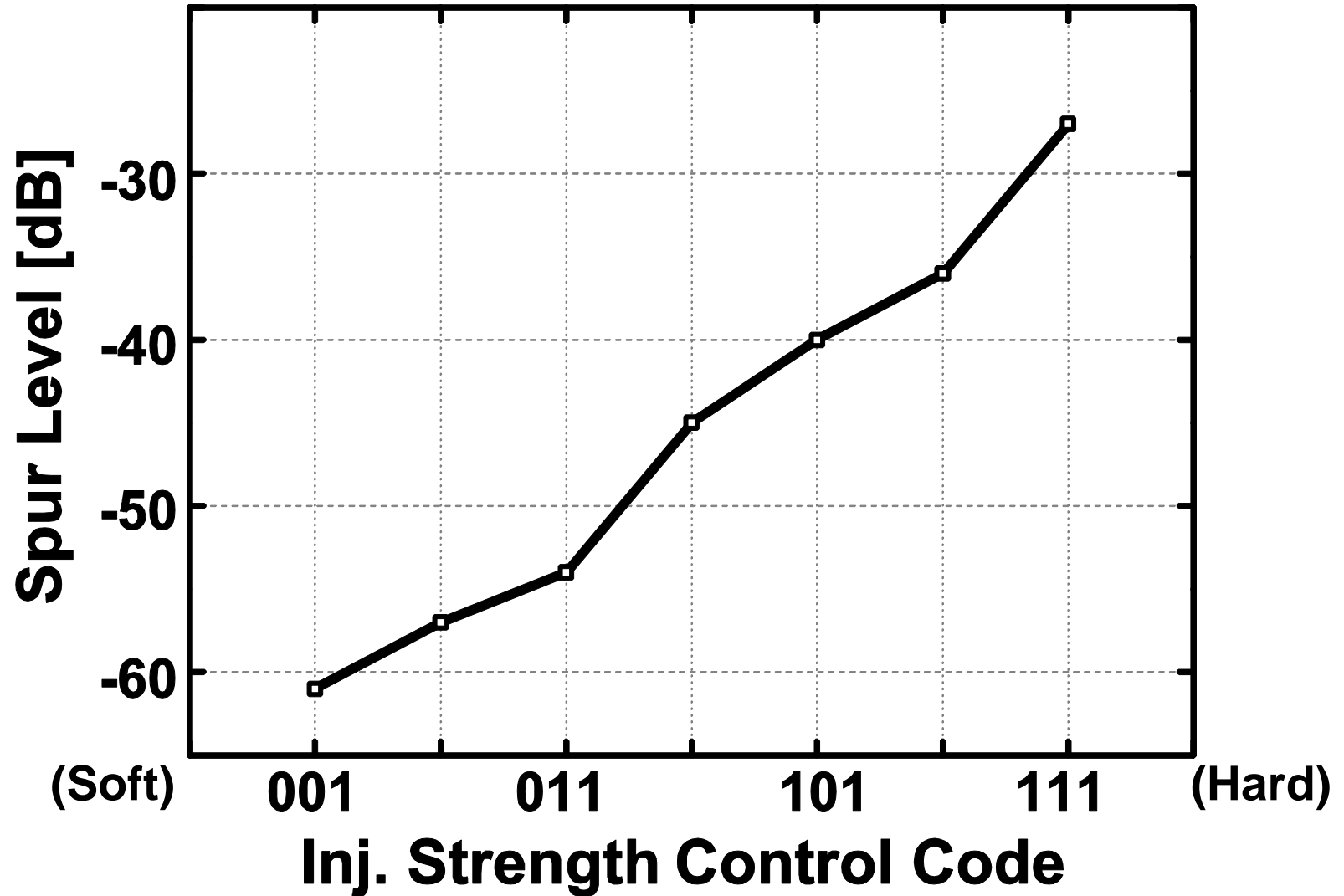


65nm CMOS technology

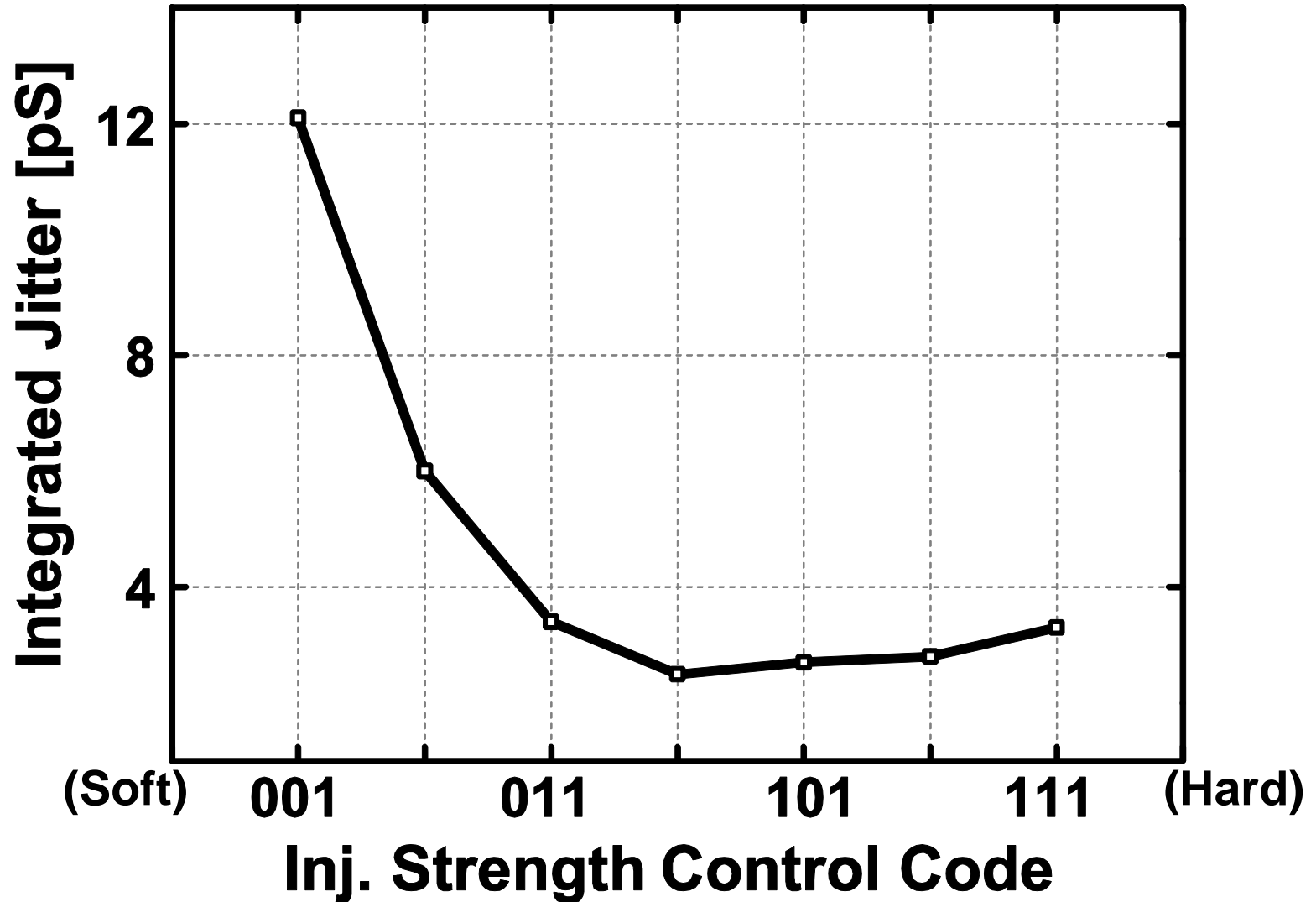
Phase Noise



Spur against Inj. Strength



Jitter against Inj. Strength



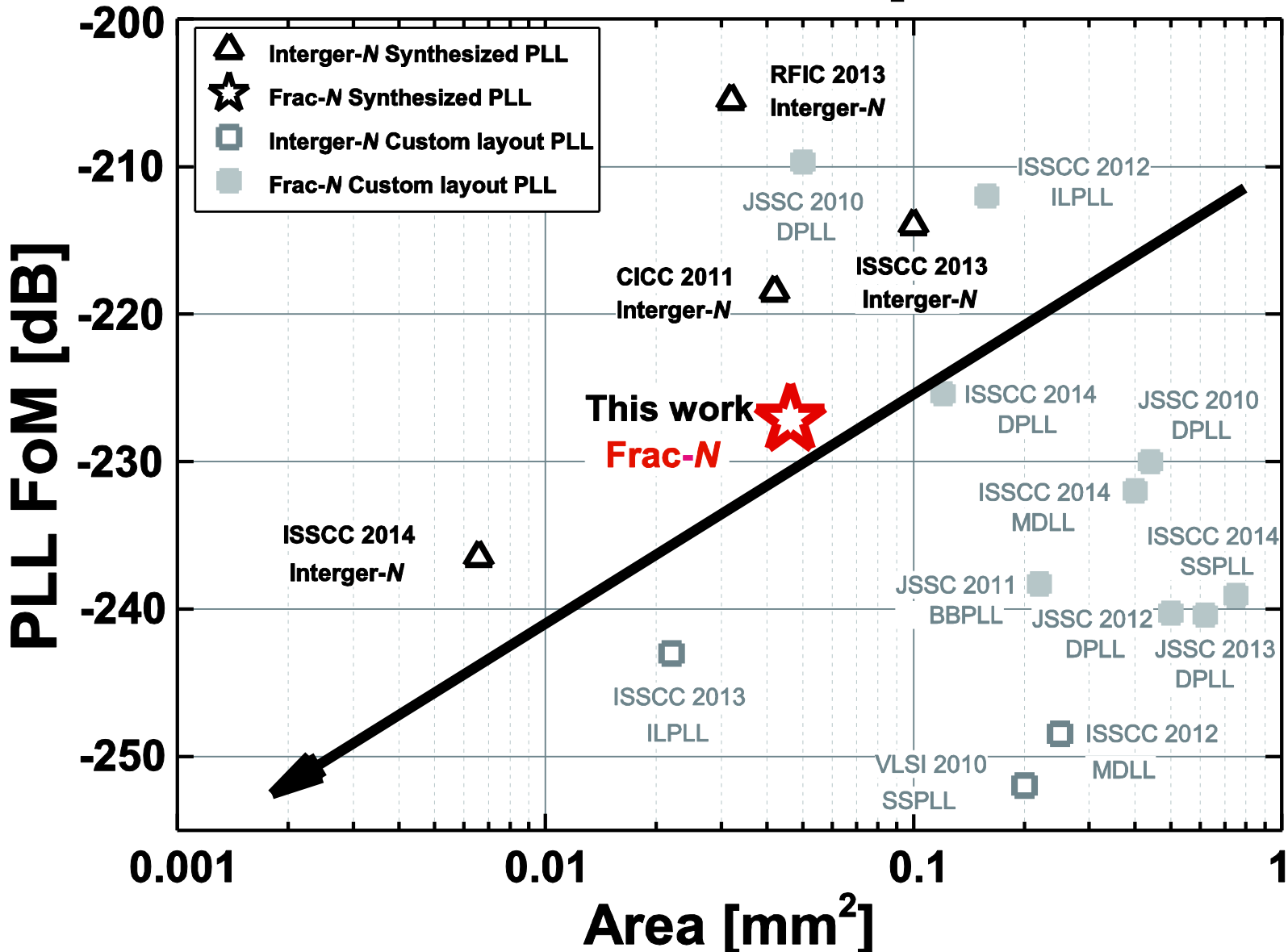
Comp. of Synthesizable PLLs

	This work	[1]	[2]
Technology	65nm	65nm	65nm
Power [mW]	2.9 @1.2576GHz	0.78 @0.9GHz	13.7 @2.5GHz
Area [mm ²]	0.048	0.0066	0.04
Integ. Jitter [ps]	2.5	1.7	3.2*
FOM [dB]	-227	-237	-219*
Topology	Soft-IL	IL	TDC-based
Type	Frac-N	Integer-N	
Synthesized?	YES		

*FOM is calculated based on RMS jitter.

[1] W. Deng, *et al.*, ISSCC 2014 [2]Y. Park, *et al.*, CICC 2011

Performance Comparison



This work
Frac-N

Conclusion

- A synthesizable fractional- N PLL with a **soft-injection locking** technique is presented.
- The soft injection locking technique provides potentials for future clock generation circuit designs.

Acknowledgement

This work is partially supported by STARC, MIC, SCOPE, MEXT, STAR, and VDEC in collaboration with Cadence Design Systems, Inc., Synopsys, Inc., and Mentor Graphics, Inc.